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## USPTO form PTO/SB/08A

Page 1 of 1 Subst. Form PTO-1449 Atty. Dkt No.: PHNL030944US Applicant(s): Michael C. VAN BEEK, et al. APPLICANT'S(S') INFORMATION **DISCLOSURE STATEMENT** Filing Date: berwith Group: uples 02/03/2006 **U.S. PATENT DOCUMENTS** Subcl Filing Date Class Initial **Document** Date Name No. 473 600 12-24-1996 AA 5,813,987 09-29-1998 Modell, et al. /IA/ 06-05-1997 5,983,120 11-09-1999 Groner, et al. 600 310 AB /IA/ Flock, et al. 600 473 01-07-2000 6,272,374 B1 08-07-2001 AC /IA/ 7IAJ 05-03-2001 02-07-2002 600 310 2002/0016533 A1 Marchitto, et al. AD 600 310 09-22-1999 08-20-2002 6,438,396 B1 Cook, et al. /IA/ ΑE FOREIGN PATENT DOCUMENTS Document Translation? Date Name No. WO 00/27276 A1 05-18-2000 Cytometrics, Inc. AF /IA/ AG WO 00/57146 A1 09-28-2000 Cytrometrics, Inc. /IA/ /IA/ WO 01/22741 A2 03-29-2001 Nadeau, et al. AH WO 02/057759 A1 07-25-2002 KPENV ΑI /IA/ EP 0 468 817 A2 01-29-1992 Booker, et al. AJ /IA/ 7IA/ EP 0 714 628 A1 06-05-1996 **TOA Medical** ΑK OTHER ART http://www.olympusmicro.com/primer/techniques/darkfieldindex.html /IA/ AL Darkfield Microscopy techniques AM ΑN Examiner: Date Considered: 10/29/2007 /lyabo Alli/ (10/29/2007) EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.